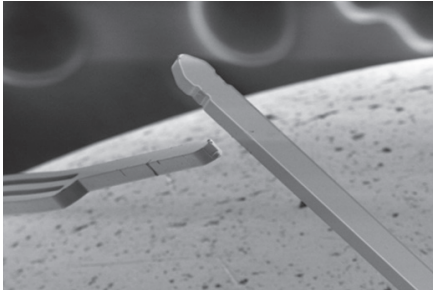


LATEST DEVELOPMENTS

Probe Card LiProbe® - The Lamella Solution

The FEINMETALL LiProbe® is the solution for advanced probing requirements. It has been designed to ensure a specific contact force as well as maintaining it over the whole lifetime. The lamella technology allows the probe to be much shorter than a conventional buckling beam and therefore is used in applications which require advanced frequency requirements.

Due to the flexibility of the probe design it is possible to equip a probe head with probes in different geometries depending on their specific function.



Advantages

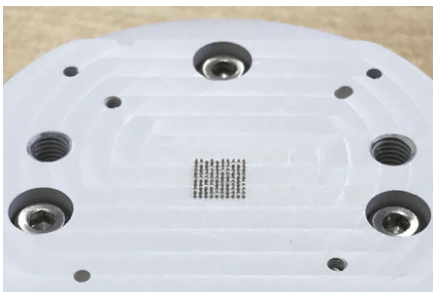
- Shortness of the probe excellent for frequency-dependent applications
- Product families with different geometries in the same probe head
- High design flexibility in terms of defining exact contact force
- Stable contact force over the lifetime as well as a low contact resistance
- FEINMETALL patented lamella design

Specifications at a glance

Min pitch of the DUT	Down to 80 µm
Max active area	Up to 105 mm x 105 mm
Capable temperature range	From -55°C to 180°C
Current carrying capability at RT	Up to 900 mA
Contact force at rec. OD	From 2.8 cN to 5.4 cN
Bandwidth analog @ -1dB limit	Up to 30 GHz

BasicProbe - Epoxy Meets Vertical

For a wide range of applications, fast and easy probing solutions are required. However, performance wise, vertical probing solutions offer many advantages compared to epoxy solutions: With the BasicProbe, FEINMETALL offers all these advantages in an easy, fast, and economic vertical probe card. The advantages of a vertical solution are clear: The stable force on the DUT compared to the linear when using an epoxy card as well as the maintenance options.



Advantages

- Stable contact force for BasicProbe
- Maintenance simplified for BasicProbe due to single exchangeable contact elements, Cantilever is limited, especially for multisite
- Flexible head-sizes (shelf etc) and designs for specific applications
- Longer lifetime compared to Cantilever
- Lead-time comparable to Cantilever

Specifications at a glance

Min pitch of the DUT	Down to 50 µm	Down to 50 µm
Diameter of the contact element	Down to 4 mil	Down to 2 mil
Max active area	Flexible	Flexible
Capable temperature range	From RT to 180°C	From RT to 85°C
Current carrying capability at RT	Up to 750 mA	Up to 750 mA
Contact force at rec. OD	Around 3 cN	Around 3 cN

Cantilever

Min pitch of the DUT	Down to 50 µm
Diameter of the contact element	Down to 4 mil
Max active area	Flexible
Capable temperature range	From RT to 180°C
Current carrying capability at RT	Up to 750 mA
Contact force at rec. OD	Around 3 cN

BasicProbe

Min pitch of the DUT	Down to 50 µm
Diameter of the contact element	Down to 2 mil
Max active area	Flexible
Capable temperature range	From RT to 85°C
Current carrying capability at RT	Up to 750 mA
Contact force at rec. OD	Around 3 cN